

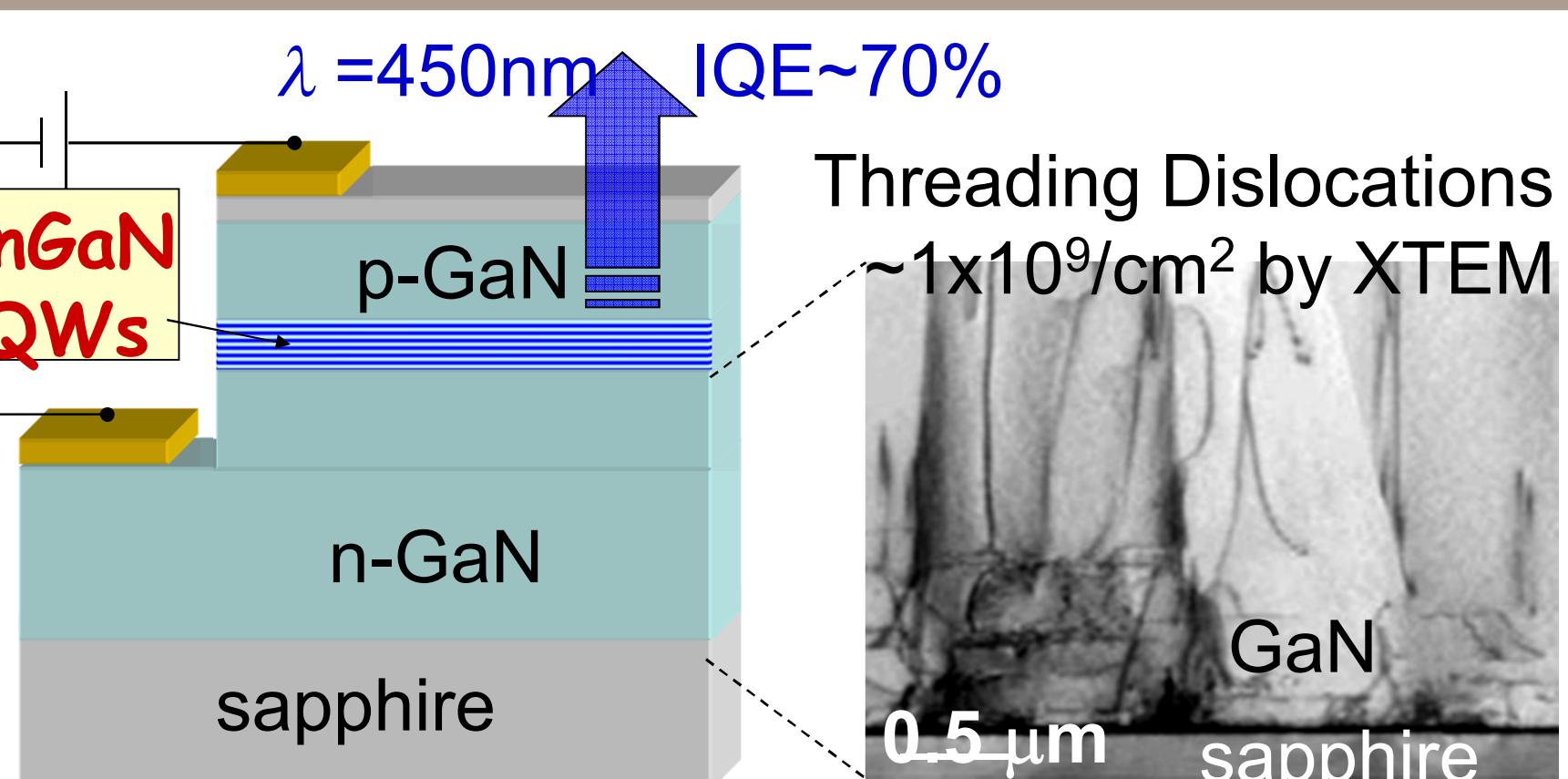
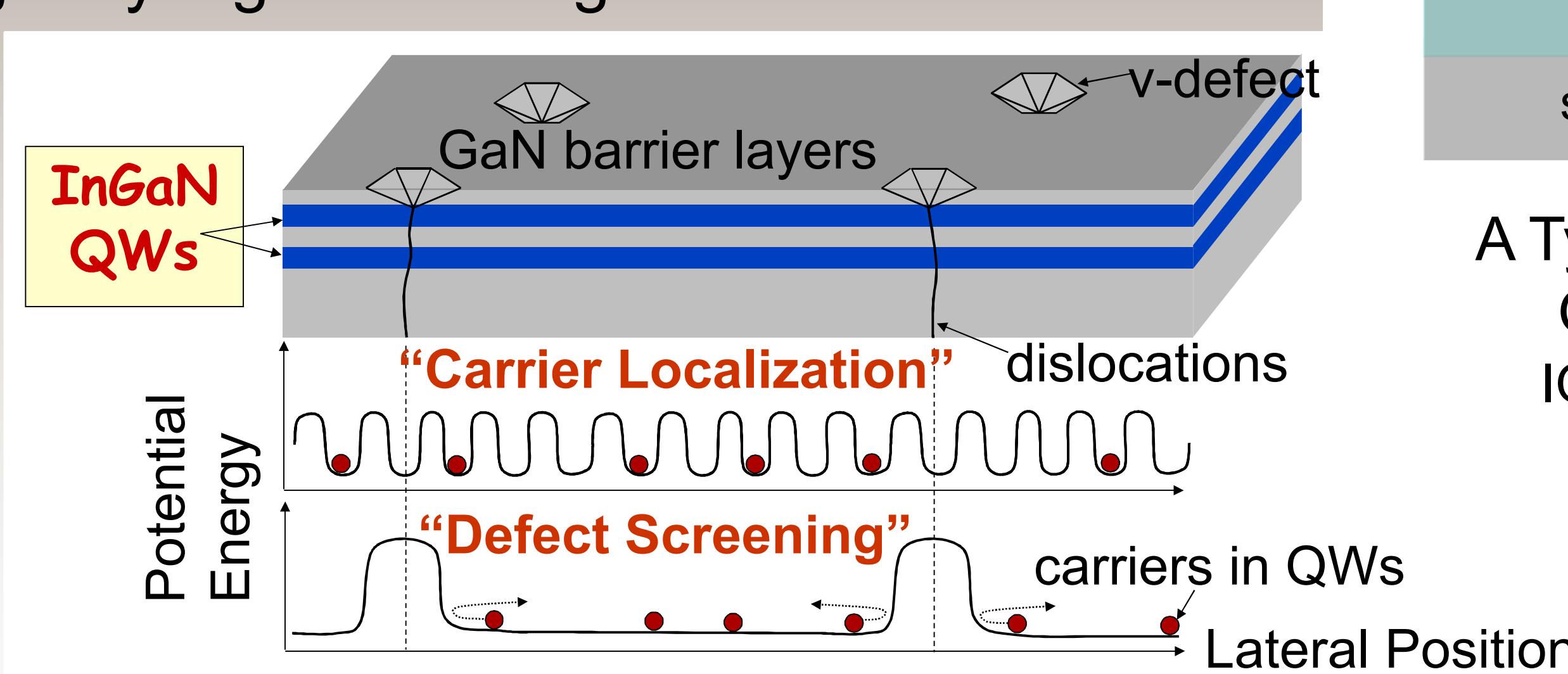
LEEM-PEEM study of surface defects, surface potential, and compositional inhomogeneities in InGaN-based heterostructures

Taisuke Ohta,¹ Stephen Lee,¹ Michael Smith,¹ Daniel Koleske,¹ Bogdan Diaconescu,¹ Jurek Sadowski,² Mary Crawford,¹ G. L. Kellogg¹

¹Sandia National Laboratories, Albuquerque, NM USA, ² Brookhaven National Laboratory, Upton, NY USA

Indium-gallium-nitride-based light-emitting devices (LEDs) are the enabling technology for an ongoing global effort to replace conventional lighting with energy-efficient Solid-State Lighting. However, the remarkable optoelectronic properties of InGaN alloys remain poorly understood, with major fundamental questions still unanswered. Foremost among these is: Why do blue-emitting InGaN alloys have high radiative efficiency despite having very high threading-dislocation densities that quench light emission in traditional semiconductors?

It is hypothesized that structural and compositional inhomogeneities localize carriers away from crystalline defects, but the nature and degree of localization, its correlation with defects, and its dependence on composition are controversial. Here, we present a low energy electron microscopy-photoemission electron microscopy study of InGaN multi-quantum-well samples.



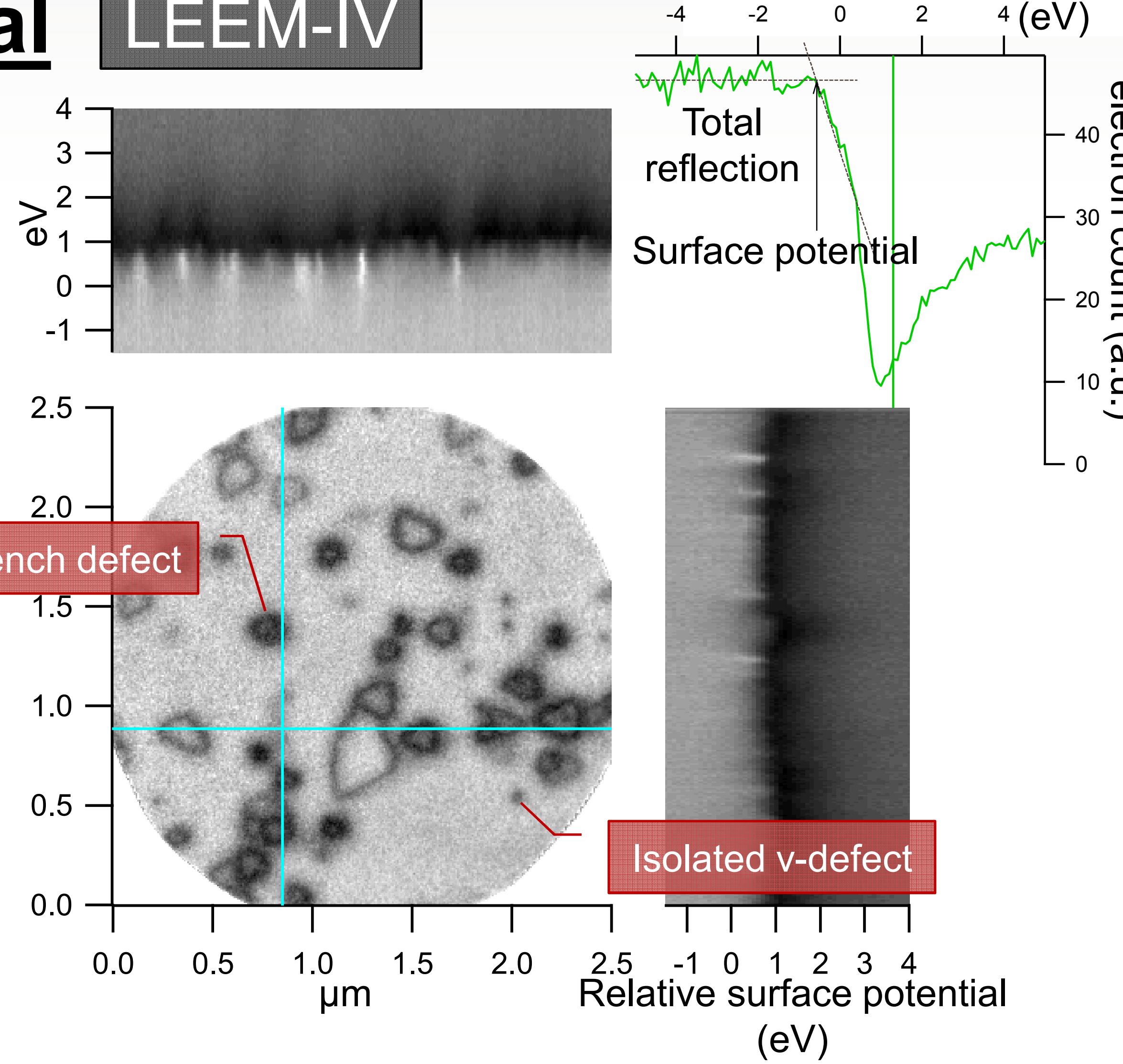
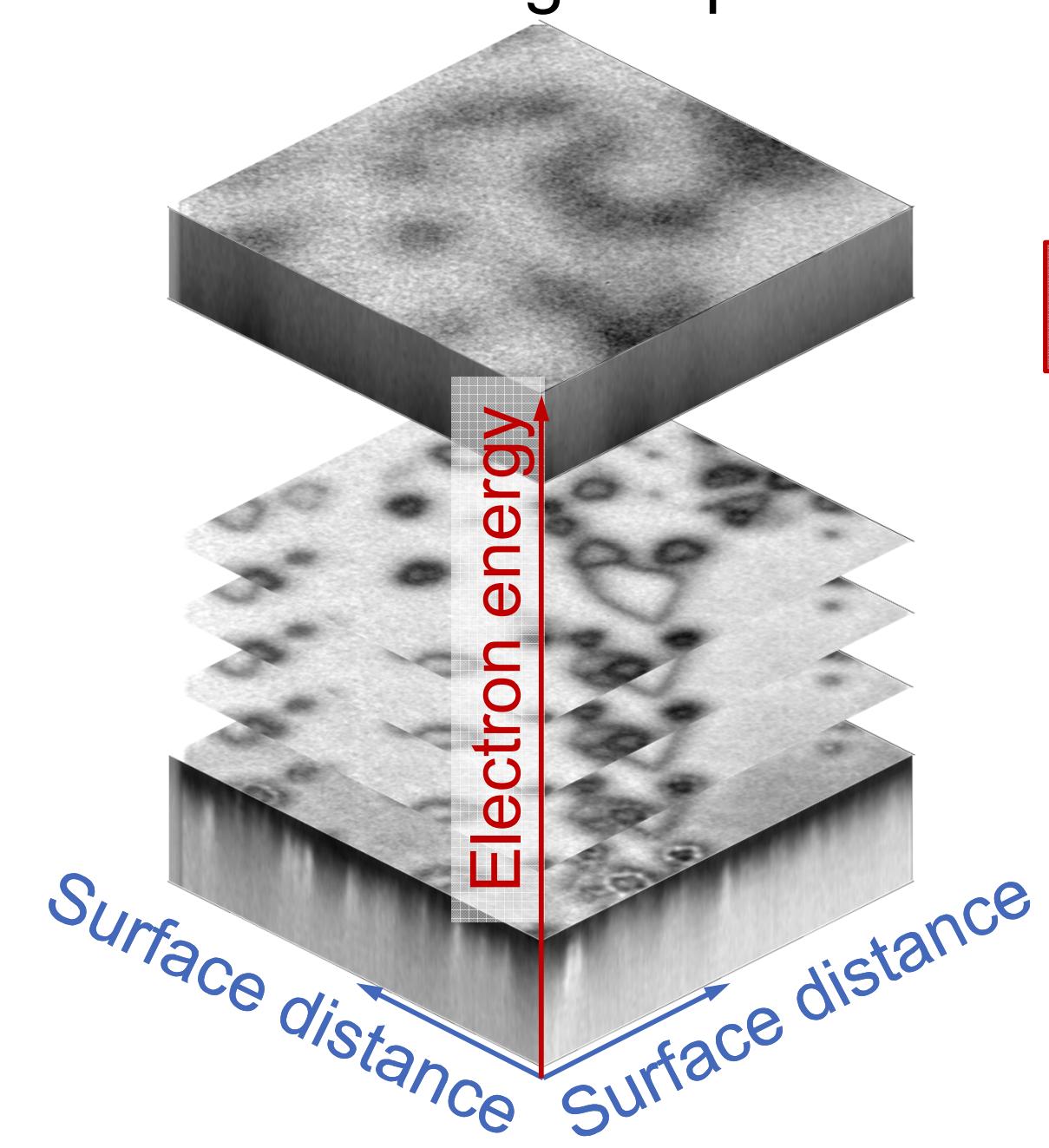
A Typical $\text{In}_{0.17}\text{Ga}_{0.83}\text{N}/\text{GaN}$ Multi-Quantum-Well (MQW) LED
IQE: internal quantum efficiency

Surface Potential

LEEM-IV

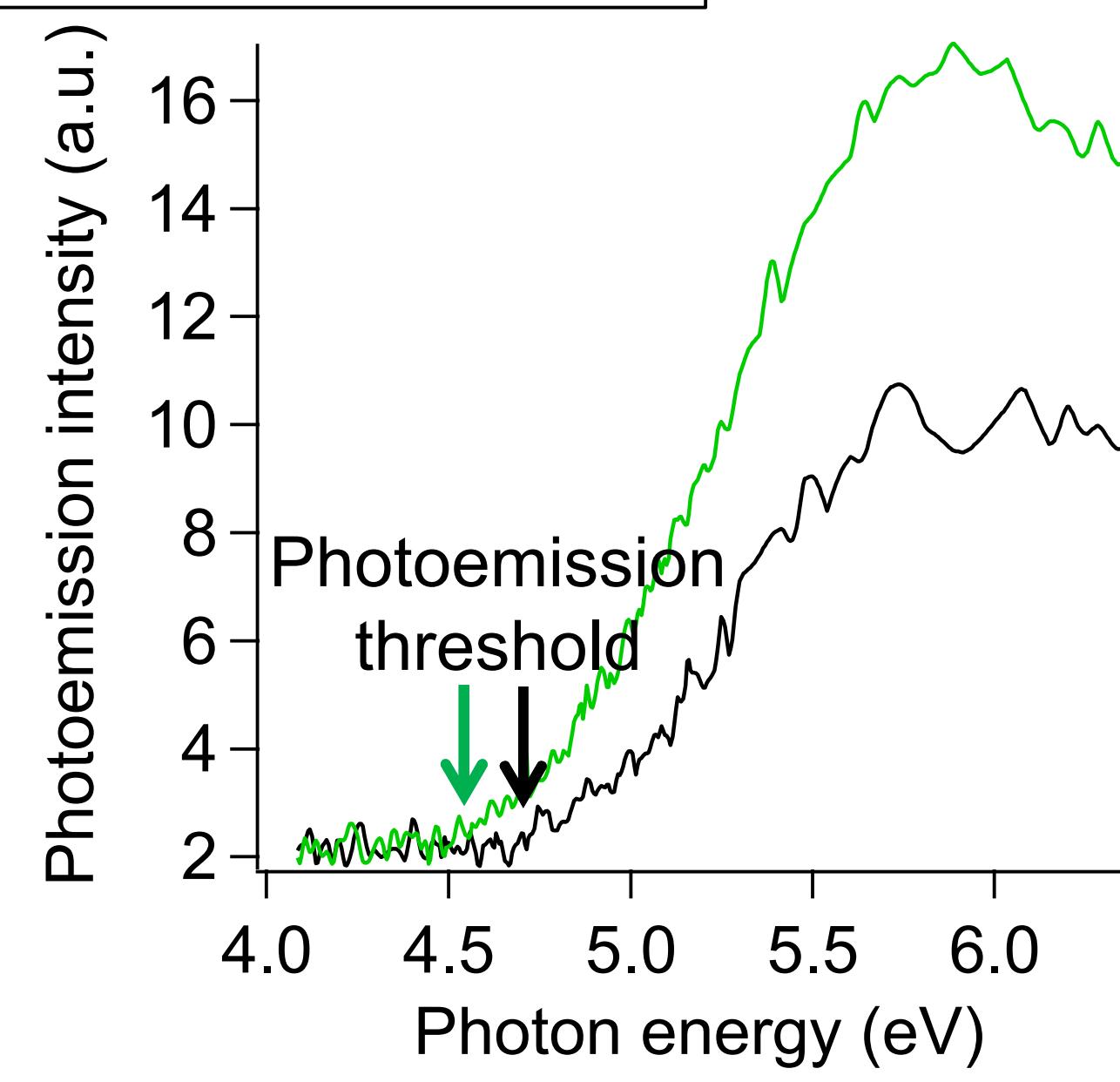
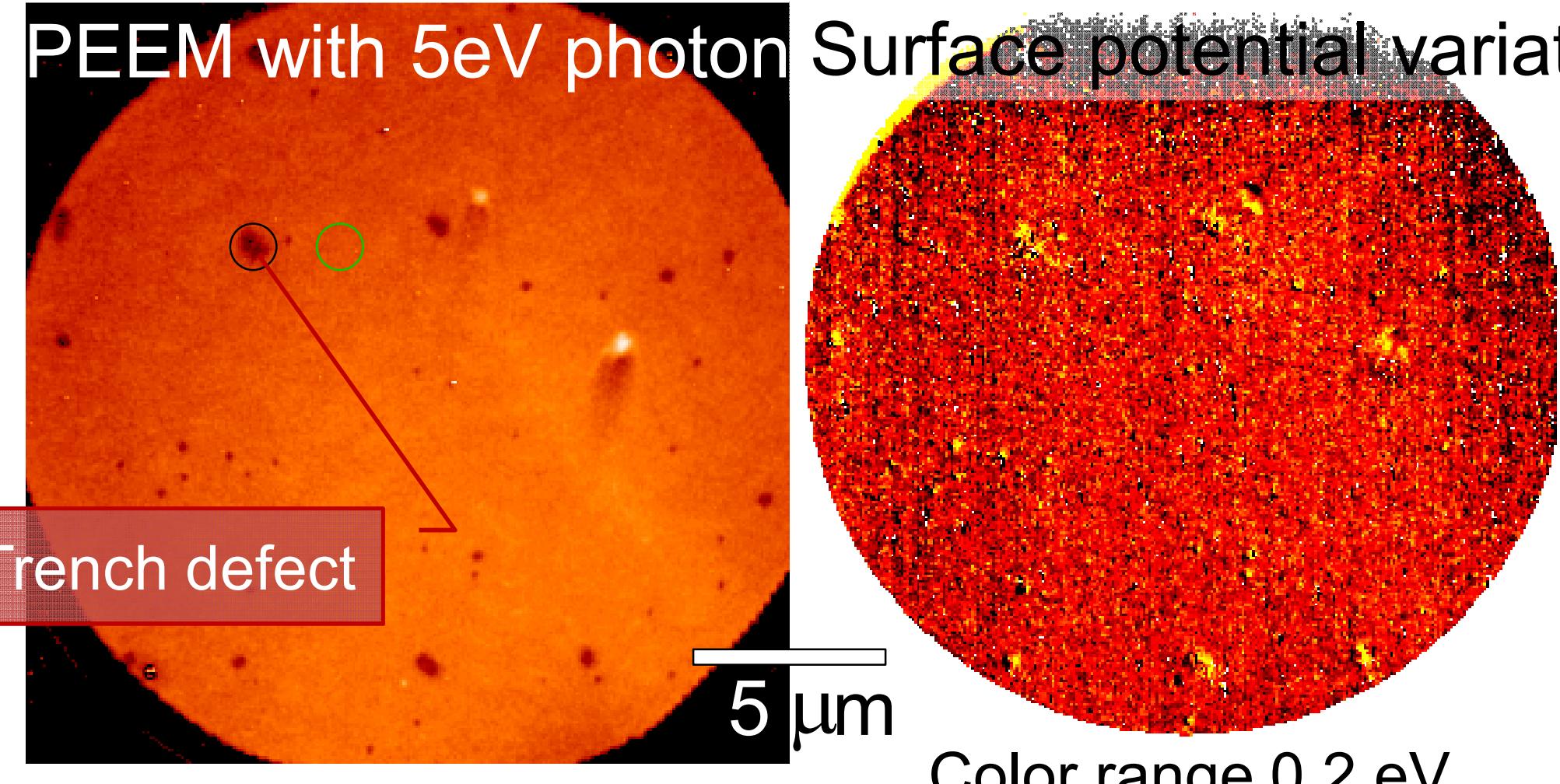
Surface potential varies around v-defects & trench defects

Trench defects: v-defects aligned in a ring shape



Threshold PEEM

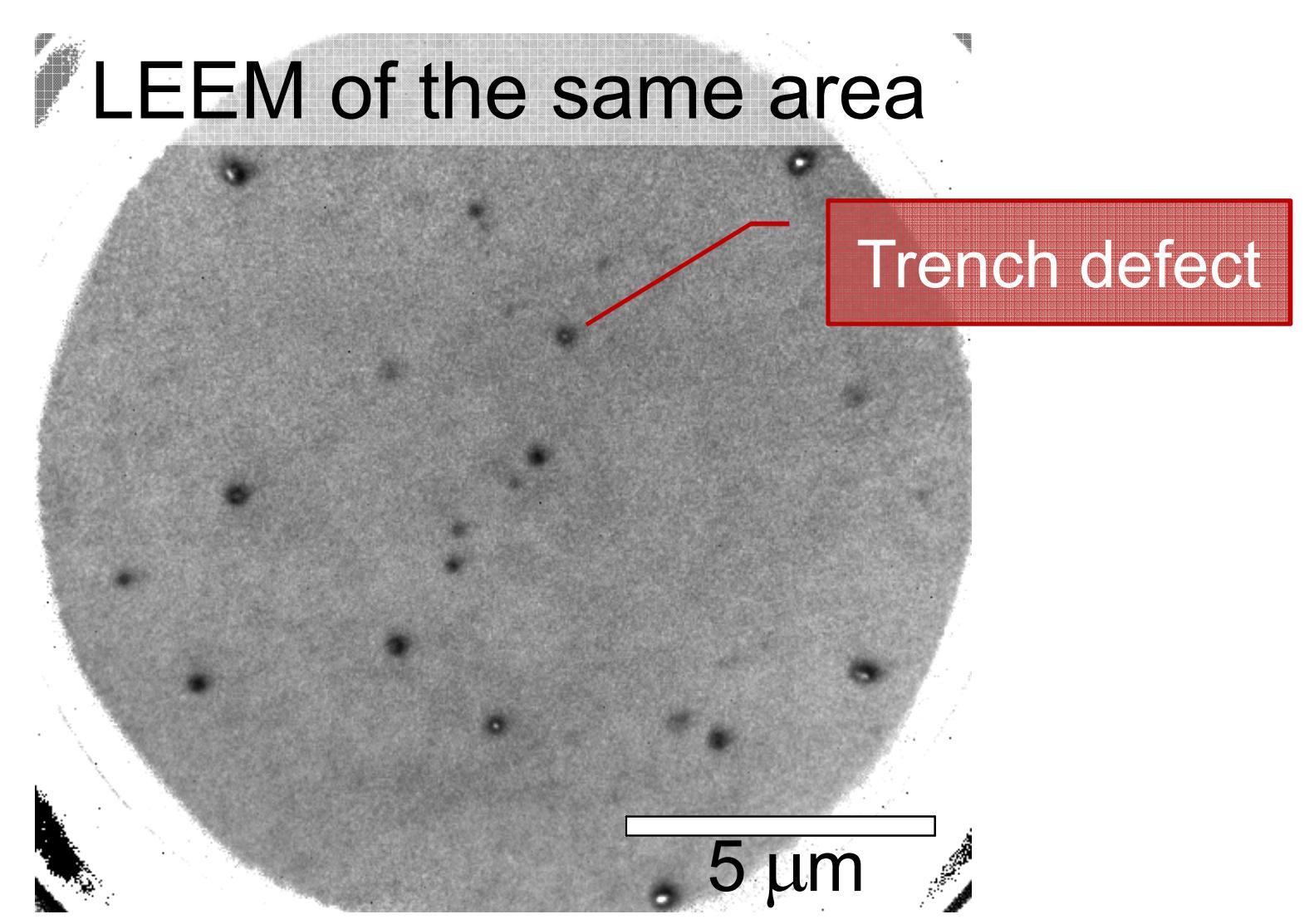
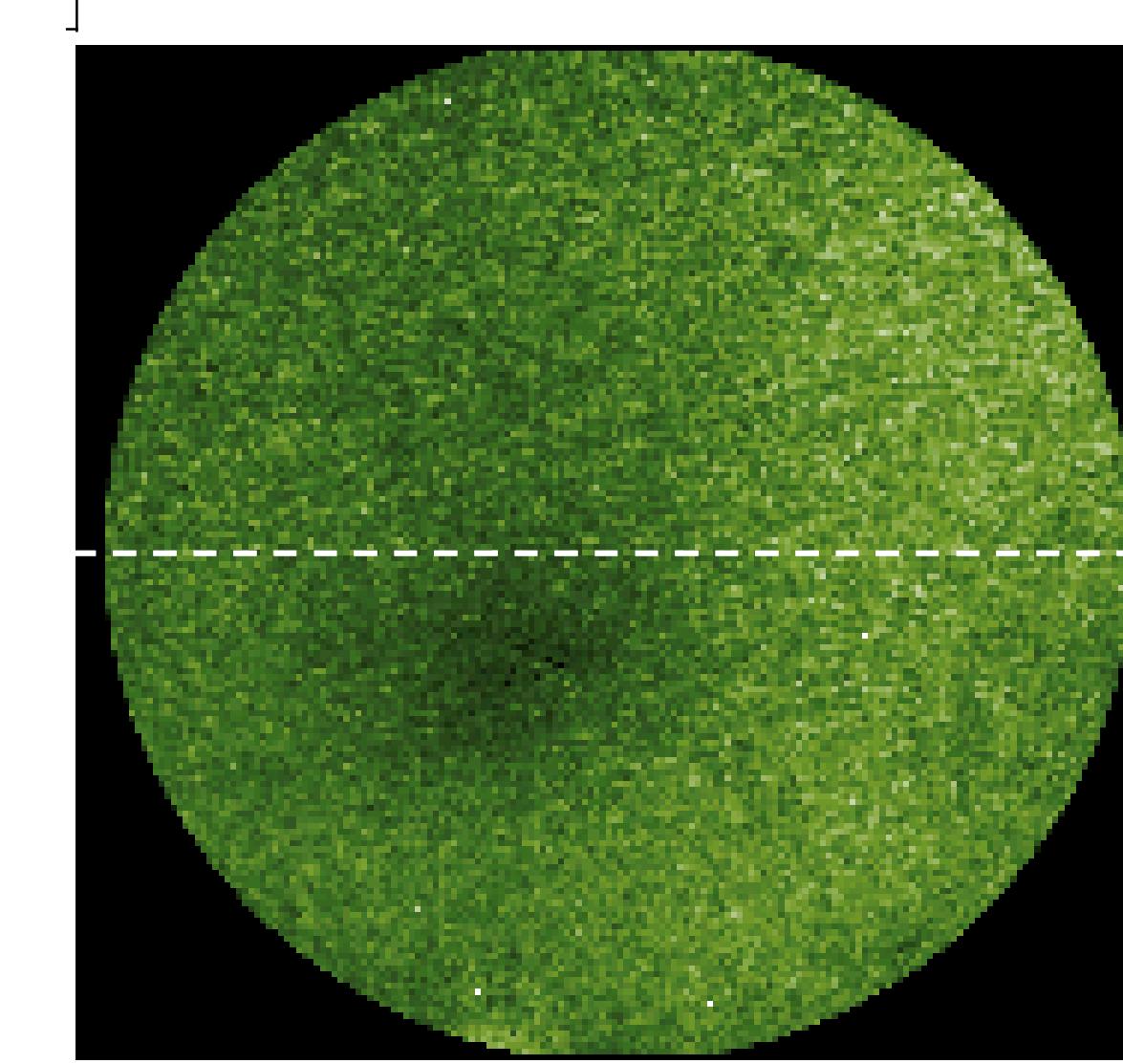
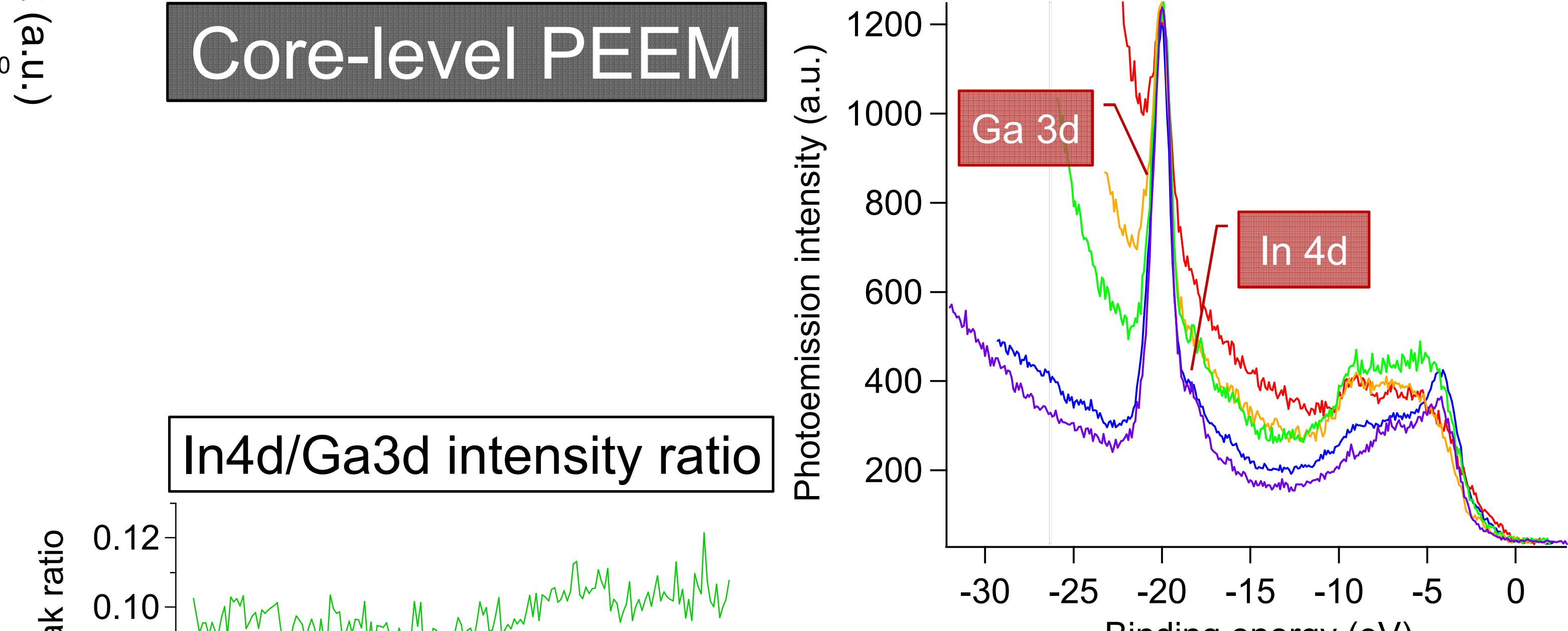
~100-150 meV higher surface potential at trench defects



Chemical Composition Analysis

Neither chemical compositional variation nor MQW's thickness variation exists at given spatial resolution & sensitivity

Core-level PEEM



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